

SEMITRANS[®] 2

IGBT Modules

SKM 100GB123D SKM 100GAL123D SKM 100GAR123D

Features

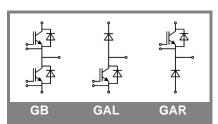
- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 x I_{cnom}
- Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (10 mm) and creepage distances (20 mm)

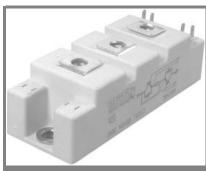
Typical Applications*

- AC inverter drives
- UPS

Absolut	e Maximum Ratings	$T_c = 2$	T _c = 25 °C, unless otherwise specified			
Symbol	Conditions	1	Values	Units		
IGBT						
V _{CES}	T _j = 25 °C T _i = 150 °C		1200	V		
I _C	T _j = 150 °C	T _{case} = 25 °C	100	A		
		T _{case} = 80 °C	90	А		
I _{CRM}	I _{CRM} =2xI _{Cnom}		150	А		
V _{GES}			± 20	V		
t _{psc}	V_{CC} = 600 V; $V_{GE} \le 20$ V; VCES < 1200 V	T _j = 125 °C	10	μs		
Inverse	Diode					
I _F	T _j = 150 °C	T _{case} = 25 °C	95	А		
		T _{case} = 80 °C	65	А		
I _{FRM}	I _{FRM} =2xI _{Fnom}		150	А		
I _{FSM}	t _p = 10 ms; sin.	T _j = 150 °C	720	А		
Freewhe	eeling Diode					
I _F	T _j = 150 °C	T _{case} = 25 °C	130	А		
		T _{case} = 80 °C	90	А		
I _{FRM}	I _{FRM} =2xI _{Fnom}		200	Α		
I _{FSM}	t _p = 10 ms; sin.	T _j = 150 °C	900	А		
Module						
I _{t(RMS)}			200	А		
T _{vj}			- 40 + 150	°C		
T _{stg}			- 40+ 125	°C		
V _{isol}	AC, 1 min.		2500	V		

Characteristics T _c =		25 °C, unless otherwise specified				
Symbol	Conditions		min.	typ.	max.	Units
IGBT						
V _{GE(th)}	$V_{GE} = V_{CE}, I_C = 2 \text{ mA}$		4,5	5,5	6,5	V
I _{CES}	V_{GE} = 0 V, V_{CE} = V_{CES}	T _j = 25 °C		0,1	0,3	mA
V _{CE0}		T _j = 25 °C		1,4	1,6	V
		T _j = 125 °C		1,6	1,8	V
r _{CE}	V _{GE} = 15 V	T _j = 25°C		14,6	18,6	mΩ
		T _j = 125°C		20	25,3	mΩ
V _{CE(sat)}	I _{Cnom} = 75 A, V _{GE} = 15 V	$T_j = °C_{chiplev.}$		2,5	3	V
C _{ies}				5	6,6	nF
C _{oes}	V_{CE} = 25, V_{GE} = 0 V	f = 1 MHz		0,72	0,9	nF
C _{res}				0,38	0,5	nF
Q _G	V _{GE} = -8V - +20V			750		nC
R _{Gint}	T _j = °C			5		Ω
t _{d(on)}				30	60	ns
t, E _{on}	R _{Gon} = 15 Ω	V _{CC} = 600V		70	140	ns
E _{on}		I _C = 75A		10		mJ
^t d(off)	R _{Goff} = 15 Ω	T _j = 125 °C		450	600	ns
t _f		V _{GE} = ± 15V		70	90	ns
E _{off}				8		mJ
R _{th(j-c)}	per IGBT				0,18	K/W





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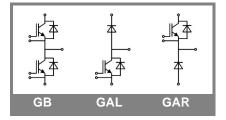
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Symbol	Conditions		min.	typ.	max.	Unite
Inverse D				typ.	max.	
	I _{Fnom} = 75 A; V _{GE} = 0 V	T _j = 25 °C _{chiplev.}		2	2,5	V
•F •EC	From Port, GE CT	$T_j = 125 \ ^{\circ}C_{chiplev.}$		_ 1,8	2,0	v
V _{F0}		$T_i = 25 \text{ °C}$		1,1	1,2	V
FU		T _i = 125 °C		,	,	v
r _F		T _i = 25 °C		12	17	mΩ
		T _j = 125 °C				mΩ
IRRM	I _F = 75 A	T _i = 125 °C		40		Α
Q _{rr}	di/dt = 800 A/µs	,		3		μC
E _{rr}	V_{GE} = 0 V; V_{CC} = 600 V					mJ
R _{th(j-c)D}	per diode				0,5	K/W
Freewhee	eling Diode					
$V_F = V_{EC}$	I _{Fnom} = 100 A; V _{GE} = 0 V	T _j = 25 °C _{chiplev.}		2	2,5	V
		$T_j = 125 \ ^\circ C_{chiplev.}$ $T_j = 25 \ ^\circ C$		1,8		V
V _{F0}				1,1	1,2	V
		T _j = 125 °C				V
r _F		T _j = 25 °C		9	13	V
		T _j = 125 °C				V
IRRM	I _F = 100 A	T _j = 25 °C		50		A
Q _{rr}	di/dt = 1000 A/µs			5		μC
Err	V _{GE} = 0 V; V _{CC} = 600 V					mJ
R _{th(j-c)FD}	per diode				0,36	K/W
Module						
L _{CE}					30	nH
R _{CC'+EE'}	res., terminal-chip	T _{case} = 25 °C		0,75		mΩ
		T _{case} = 125 °C		1		mΩ
R _{th(c-s)}	per module				0,05	K/W
M _s	to heat sink M6		3		5	Nm
M _t	to terminals M5		2,5		5	Nm
w					160	g

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our personal.



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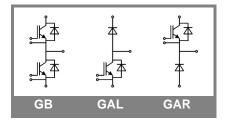
SKM 100GAR123D

Features

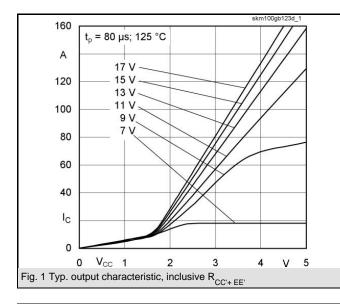
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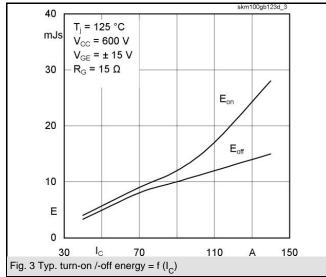
Typical Applications*

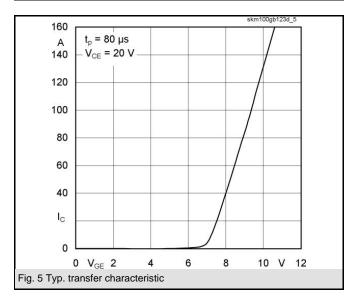
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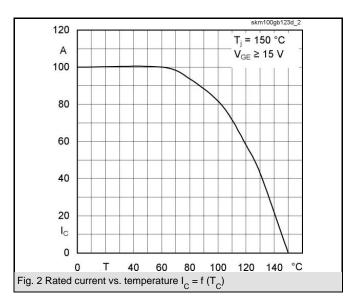


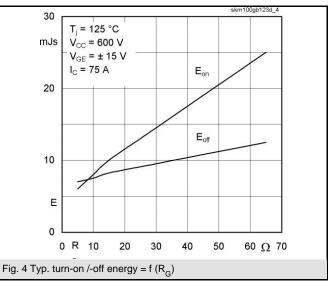
Z _{th}			
Symbol	Conditions	Values	Units
Z _{th} (i a)			
Z Ri Ri	i = 1	162	mk/W
R _i	i = 2	14	mk/W
R _i	i = 3	2,7	mk/W
R _i	i = 4	1,3	mk/W
tau _i	i = 1	0,204	s
tau _i	i = 2	0,0242	S
tau	i = 3	0,0013	S
tau _i	i = 4	0	s
Z R _i th(j-c)D			
R _i	i = 1	320	mk/W
R _i	i = 2	150	mk/W
R _i	i = 3	0,0265	mk/W
R _i	i = 4	3,5	mk/W
tau _i	i = 1	0,05	S
taui	i = 2	0,0104	S
tau _i	i = 3	0,0034	s
tau	i = 4	0,0003	s

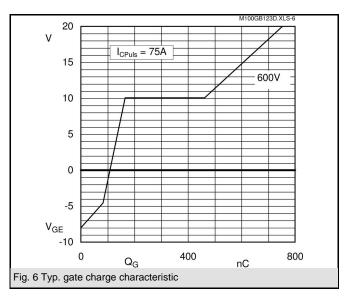




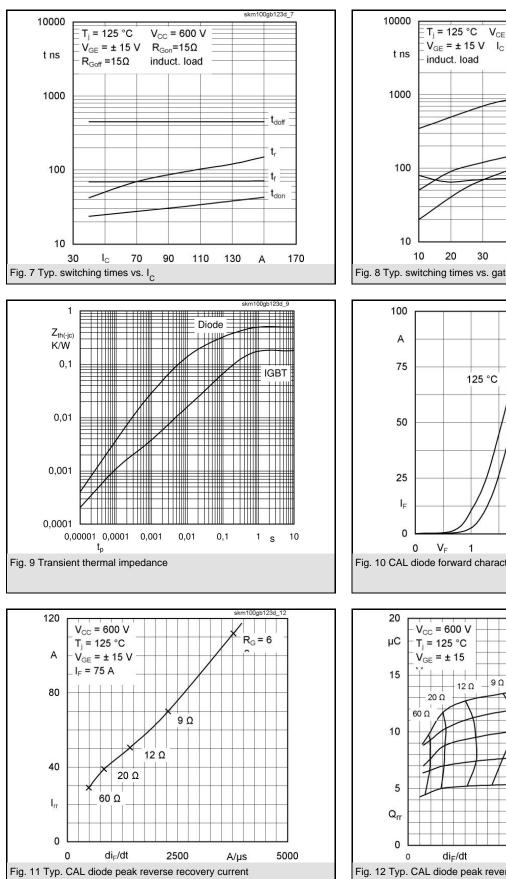




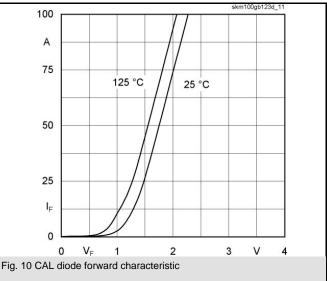


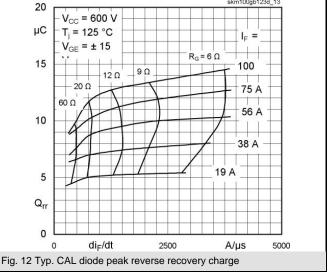


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 $f_{J} = 125 \circ C \quad V_{CE} = 600 V$ $f_{J} = 125 \circ C \quad V_{CE} = 600 V$ $f_{J} = 125 \circ C \quad V_{CE} = 75 A$





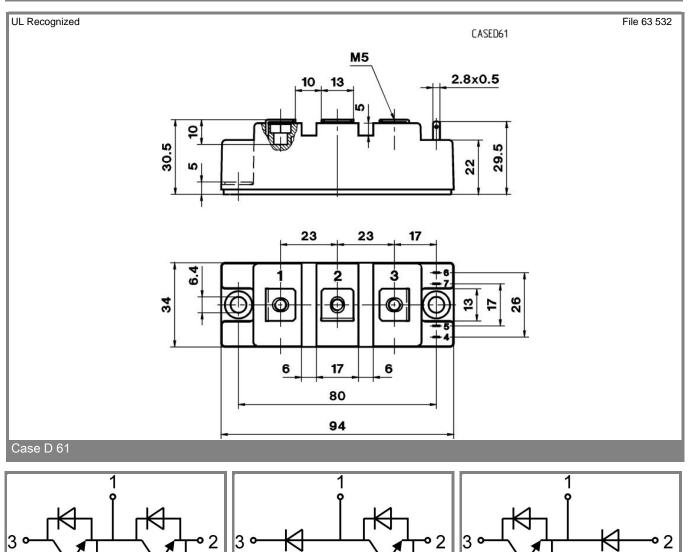
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6 7

Case D 61

GAL



C

GAR

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d

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Case D 62 (→ D 61)

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